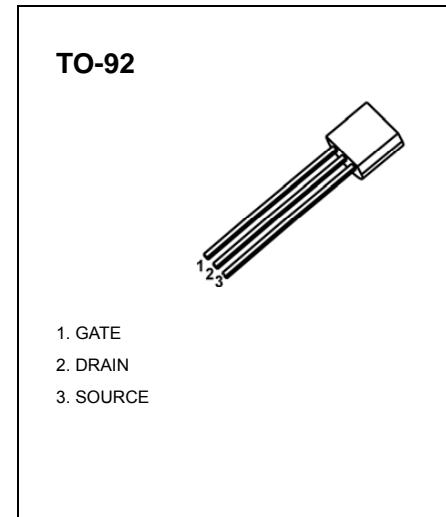


TO-92 Plastic-Encapsulate MOSFETS

CJV01N60 N-Channel Power MOSFET

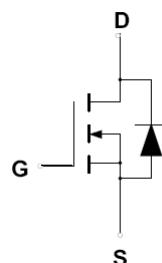
General Description

The high voltage MOSFET uses an advanced termination scheme to provide enhanced voltage-blocking capability without degrading performance over time. In addition , this advanced MOSFET is designed to withstand high energy in avalanche and commutation modes . The new energy efficient design also offers a drain-to-source diode with a fast recovery time. Designed for high voltage, high speed switching applications in power suppliers, converters and PWM motor controls , these devices are particularly well suited for bridge circuits where diode speed and commutating safe operating areas are critical and offer additional and safety margin against unexpected voltage transients.



FEATURES

- Robust High Voltage Termination
- Avalanche Energy Specified
- Source-to-Drain Diode Recovery Time Comparable to a Discrete Fast Recovery Diode
- Diode is Characterized for Use in Bridge Circuits
- I_{DSS} and $V_{DS(on)}$ Specified at Elevated Temperature



Maximum ratings ($T_a=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Value	Unit
Drain-Source Voltage	V_{DS}	600	V
Gate-Source Voltage	V_{GS}	± 30	
Continuous Drain Current	I_D	1	A
Pulsed Drain Current	I_{DM}	9	
Power Dissipation	P_D	0.625	W
Single Pulsed Avalanche Energy*	E_{AS}	20	mJ
Thermal Resistance from Junction to Ambient	R_{thJA}	200	°C/W
Junction Temperature	T_J	150	°C
Storage Temperature	T_{stg}	-50 ~+150	

* E_{AS} condition: $T_J=25^\circ\text{C}$, $V_{DD}=100\text{V}$, $V_{GS}=10\text{V}$, $L=10\text{mH}$, $I_{AS}=2\text{A}$, $R_G=25\Omega$

Electrical characteristics ($T_a=25^\circ\text{C}$ unless otherwise noted)

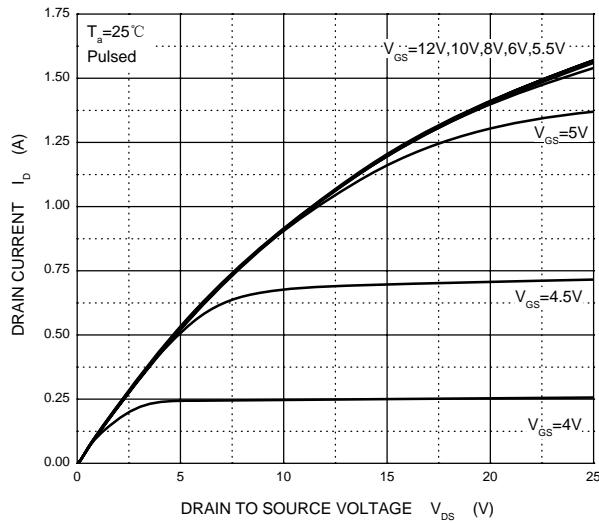
Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_{\text{D}} = 250\mu\text{A}$	600			V
Gate-Threshold Voltage (note1)	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_{\text{D}} = 250\mu\text{A}$	2.0		4.0	
Gate-Body Leakage Current (note1)	I_{GSS}	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 20\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = 600\text{V}, V_{\text{GS}} = 0\text{V}$			0.10	μA
Drain-Source On-State Resistance (note1)	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}} = 10\text{V}, I_{\text{D}} = 0.6\text{A}$			10	Ω
Forward Transconductance (note1)	g_{fs}	$V_{\text{DS}} = 50\text{V}, I_{\text{D}} = 0.5\text{A}$	0.5			S
Input Capacitance	C_{iss}	$V_{\text{DS}} = 25\text{V}, V_{\text{GS}} = 0\text{V}, f = 1\text{MHz}$		210		pF
Output Capacitance	C_{oss}			28		
Reverse Transfer Capacitance	C_{rss}			4.2		
Turn-On Delay Time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = 300\text{V}, I_{\text{D}} = 1\text{A}, V_{\text{GS}} = 10\text{V}, R_{\text{G}} = 18\Omega$		8		nS
Rise Time	t_{r}			21		
Turn-Off Delay Time	$t_{\text{d}(\text{off})}$			18		
Fall Time	t_{f}			24		
Forward on Voltage(note1)	V_{SD}	$V_{\text{GS}} = 0\text{V}, I_{\text{S}} = 1\text{A}$			1.5	V

Notes:

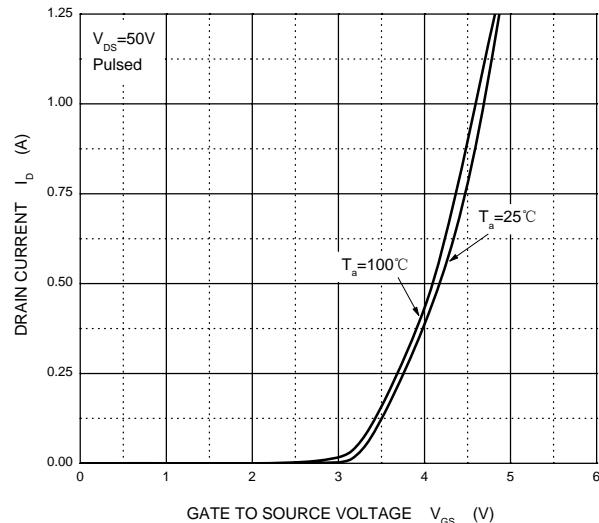
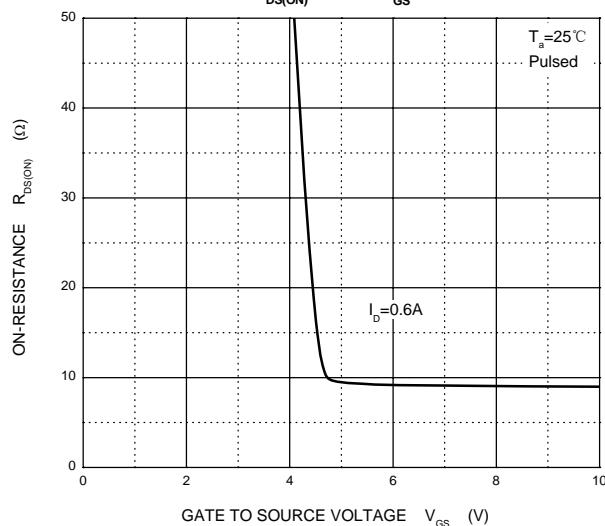
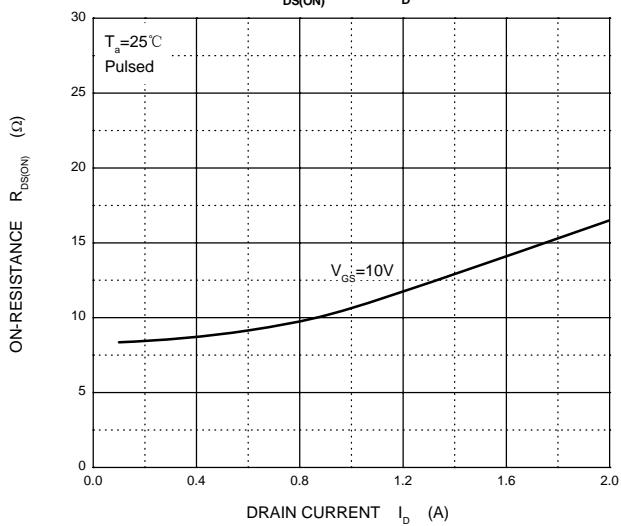
1. Pulse Test : Pulse Width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.



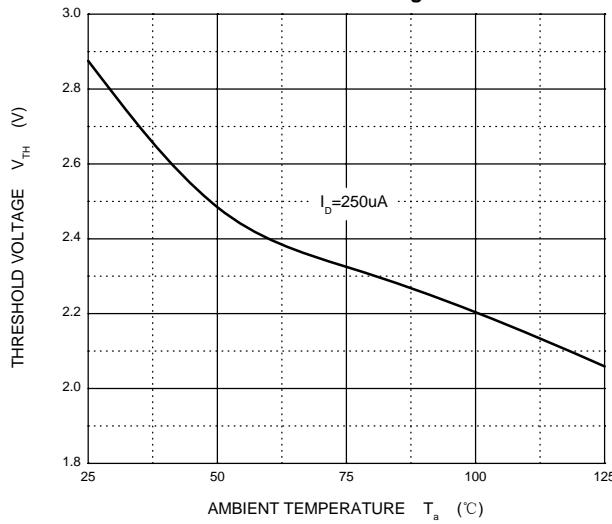
Output Characteristics



Transfer Characteristics

 $R_{DS(ON)}$ — V_{GS}  $R_{DS(ON)}$ — I_D 

Threshold Voltage

 I_s — V_{SD} 